

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Art Unit: 2878

Examiner:

REQUEST FOR CORRECTION OF INVENTORSHIP
UNDER 37 CFR 1.48 (a)

Applicants respectfully request that Mr. Klaus DREISEWERD be added as an inventor in this application under 37 CFR 1.48(a). Accompanying this request for correction of inventorship is applicants' new Declaration under 37 CFR 1.63, a statement from each inventor that this error was without deceptive intent and the written consent of the assignee for this inventorship change.

The payment (the \$130.00 fee set forth in 37 C.F.R. 1.17(i) for processing fee for taking action under 37 CFR 1.48(a)) is currently due. The Commissioner is hereby authorized to charge this \$130.00 fee as well as any other fee that may be required to keep this application in force to the Credit Card number listed on the attached Credit Card Payment Form (PTO-2038 Form),

Request for Correction of Inventorship
under 37 CFR 1.48(a)
Application No.: 10/521,563
Page 2


referencing Attorney Docket No. 0075/021001. A duplicate copy of this paper is enclosed.

Applicants submit that all of the requirements for correction of inventorship have been met and therefore, applicants respectfully request that this request for correction of inventorship be granted.

If there are any questions or concerns regarding this matter, the Examiner is requested to telephone the undersigned at the telephone number listed below.

Respectfully submitted,

Date: June 27, 2006


Randolph A. Smith
Reg. No. 32,548

SMITH PATENT OFFICE
1901 Pennsylvania Ave., N.W.
Suite 901
Washington, DC 20006-3433
Telephone: 202/530-5900
Facsimile: 202/530-5902
Knebel062706



PATENT
ATTORNEY DOCKET NO: 0075/021001

COMBINED DECLARATION AND POWER OF ATTORNEY

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are as stated below next to my name,

I believe I am the original, first and sole inventor (if only one name is listed below) or an original, first and joint inventor (if plural names are listed below) of the subject matter which is claimed and for which a patent is sought on the invention entitled METHOD FOR LOCALLY HIGHLY RESOLVED, MASS-SPECTROSCOPIC CHARACTERIZATION OF SURFACES USING SCANNING PROBE TECHNOLOGY, the specification of which

___ is attached hereto.

X was filed on January 19, 2005 as Application Serial No. 10/521,563

and was amended on _____.

___ was described and claimed in PCT International Application No. _____
filed on _____ and as amended under PCT Article 19 on _____

I hereby state that I have reviewed and understand the contents of the above-identified specification, including the claims, as amended by any amendment referred to above.

I acknowledge the duty to disclose all information I know to be material to patentability in accordance with Title 37, Code of Federal Regulations, Section 1.56.

I hereby claim foreign priority benefits under 35 U.S.C. 119(a)-(d) or 365(b) of any foreign application(s) for patent or inventor's certificate, or 365(a) of any PCT international application which designated at least one country other than the United States of America, listed below and have also identified below, by checking below, any foreign application for patent or inventor's certificate, or of any PCT international application having a filing date before that of the application on which priority is claimed.

<u>102 34 507.4</u>	<u>Germany</u>	<u>July 24, 2002</u>	<u>X</u>	_____
<u>PCT/DE2003/002493</u>	<u>WIPO</u>	<u>July 24, 2003</u>	<u>X</u>	_____
_____	_____	_____	_____	_____
_____	_____	_____	_____	_____
(Application Number)	(Country)	(Filing Date)	(Priority Claimed)	(Priority Not Claimed)

I hereby appoint the following attorneys and/or agents to prosecute this application and to transact all business in the Patent and Trademark Office connected therewith: Randolph A. Smith, Reg. No. 32,548.

Address all telephone calls to Randolph A. Smith at telephone number 202-530-5900.

Address all correspondence to Randolph A. Smith, Smith Patent Office, 1901 Pennsylvania Ave., N.W., Suite 901, Washington, D.C. 20006-3433 (Fax: 202-530-5902)

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patents issued thereon.

Full Name of Inventor: Detlef KNEBEL

Inventor's Signature: *Detlef Knebel* Date: June 15, 2006

Residence Address: Berlin, Germany

Citizen of: Germany

Post Office Address: c/o JPK Instruments AG, Bouchéstrasse 12, 12435 Berlin Germany

Full Name of Inventor: Matthias AMREIN

Inventor's Signature: *M. Amrein* Date: June 15, 2006

Residence Address: Calgary, Canada

Citizen of: Switzerland

Post Office Address: c/o JPK Instruments AG, Bouchéstrasse 12, 12435 Berlin Germany

Full Name of Inventor: ~~Matthias AMREIN~~

Inventor's Signature: *Klaus Gressen* Date: June 12, 2006

Residence Address: Münster, Germany

Citizen of: Germany

Post Office Address: c/o JPK Instruments AG, Bouchéstrasse 12, 12435 Berlin Germany



PATENT
ATTORNEY DOCKET NO. 0075/021001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Detlef KNEBEL et al. Art Unit: 2878
Application No.: 10/521,563 Examiner:
Title: METHOD FOR LOCALLY HIGHLY RESOLVED, MASS-SPECTROSCOPIC
CHARACTERIZATION OF SURFACES USING SCANNING PROBE
TECHNOLOGY

International Application No.: PCT/DE2003/002493
International Filing Date : July 24, 2003
Priority Date : July 24, 2002
U.S. Filing Date : January 19, 2005

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

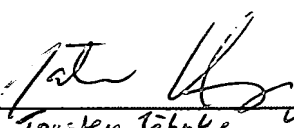
WRITTEN CONSENT OF ASSIGNEE FOR CORRECTION OF INVENTORSHIP

Sir:

I, Toosten Jägle, am the authorized representative of
JPK Instruments AG, the Assignee of this application. JPK
Instruments AG consents to the change of inventorship in this
application.

Respectfully submitted,

Date: 16/05/06


Name : Toosten Jägle, Jörn Kamp
Title: CTO
JPK Instruments AG
Bouchéstrasse 12
12435 Berlin Germany

ASSIGNMENT

For good and valuable consideration, the receipt and sufficiency of which are hereby acknowledged, the undersigned hereby assign(s), transfer(s) and set(s) over to:

JPK Instruments AG

having the address:

Bouchéstrasse 12
12435 Berlin Germany

(hereinafter designated as the "ASSIGNEE"), its successors and assigns, the entire right, title, and interest for the United States in the invention, and all applications for patent and any Letters Patent which may be granted therefor, including said application, and all United States Letters Patents which may be granted therefore, and all divisions, reissues, continuations and extensions thereof, the said interest being the entire ownership of said Letters Patent when granted to be held by said ASSIGNEE, its successors; assigns or their legal representatives, to the full end of the term for which said Letters Patent may be granted, as fully and entirely as the same would have been and enjoyed by Assignor(s) if this assignment had not been made, the application being known by the Title:

METHOD FOR LOCALLY HIGHLY RESOLVED, MASS-SPECTROSCOPIC
CHARACTERIZATION OF SURFACES USING SCANNING PROBE
TECHNOLOGY

Attorney Docket No. 0075/021001

for which the undersigned has/have executed an application for patent in the United States of America on the same day herewith. Where this instrument is not filed concurrently with the application, the following identifying information may be added after execution:

Application No. 10/521,563 Filing Date: January 19, 2005

1. The undersigned hereby agree(s) to sign and execute any further documents and instruments which may be necessary, lawful and proper in the prosecution of said above-named application or in the preparation and prosecution of any continuing, continuation-in-part, substitute, divisional, renewal, reviewed or reissue application or in any amendments, extension of interference proceedings, or otherwise to secure the title thereto to the ASSIGNEE.

2. The undersigned agree(s) to execute all papers and documents and perform any act that may be necessary in connection with claims or provisions of the International Convention for Protection of Industrial Property or similar agreements.

3. The undersigned agree(s) to perform all affirmative acts that may be necessary to obtain a grant of a valid United States patent to the ASSIGNEE.

4. The undersigned hereby authorize(s) and request(s) the Commissioner of Patents and Trademarks in the United States to issue any and all Letters Patents resulting from said application or any division or divisions or continuing applications thereof to the said ASSIGNEE.


5. The undersigned hereby grant(s) to Randolph A. Smith and Smith Patent Office the power to insert on this assignment any further identification which may be necessary or desirable in order to comply with the rules of the United States Patent and Trademark Office for recordation of this document.

In witness whereof, executed by the undersigned on the date(s) opposite the undersigned name(s).

June 15/2006
Date


Typed Name: Detlef KNEBEL

June 5/06
Date

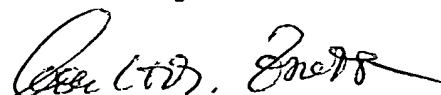

Typed Name: Matthias AMRETN

June 12/2006
Date


Typed Name: ~~Notary Public~~

This assignment may be signed before a U.S. Notary Public or before at least ~~two witnesses~~ who also sign here:

June 15/2006
Date


Typed Name:

June 15/2006
Date


Typed Name:



PATENT
ATTORNEY DOCKET NO. 0075/021001

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Applicants: Detlef KNEBEL et al. Art Unit: 2878
Application No.: 10/521,563 Examiner:
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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

STATEMENT FROM INVENTOR REGARDING INVENTORSHIP ERROR


Sir:

I, Detlef KNEBEL, am an inventor of the invention in this application. I hereby state that the inventorship error occurred without deceptive intention.

Respectfully submitted,

Date:

June 15/2006



Detlef KNEBEL
JPK Instruments AG
Bouchéstrasse 12
12435 Berlin Germany



PATENT
ATTORNEY DOCKET NO. 0075/021001

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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

STATEMENT FROM INVENTOR REGARDING INVENTORSHIP ERROR


Sir:

I, Matthias AMREIN, am an inventor of the invention in this application. I hereby state that the inventorship error occurred without deceptive intention.

Respectfully submitted,

Date:

June 05, 06


Matthias AMREIN
JPK Instruments AG
Bouchéstrasse 12
12435 Berlin Germany



PATENT
ATTORNEY DOCKET NO. 0075/021001

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Applicants: Detlef KNEBEL et al. Art Unit: 2878
Application No.: 10/521,563 Examiner:
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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

STATEMENT FROM INVENTOR REGARDING INVENTORSHIP ERROR

Sir:

I, Klaus DREISEWERD, am an inventor of the invention in this application. I hereby state that the inventorship error occurred without deceptive intention.

Respectfully submitted,

Date:

June 12/2006

Klaus DREISEWERD
JPK Instruments AG
Bouchéstrasse 12
12435 Berlin Germany